



20V PNP LOW SATURATION TRANSISTOR AND 40V, 1A SCHOTTKY DIODE COMBINATION DUAL

#### Features

- **PNP** Transistor
  - $V_{CEO} = -20V$
  - $R_{SAT} = 64m\Omega$
  - $I_{\rm C} = -3.5 {\rm A}$
- Schottky Diode
  - $V_R = 40V$
  - V<sub>F</sub>= 500mv (@1A)
  - $I_{\rm C} = 1 \rm A$
- I<sub>C</sub> = -3.5A Continuous Collector Current
- Low Saturation Voltage (-220mV @ -1A)
- hFE characterized up to -6A
- Low V<sub>F</sub>, fast switching Schottky
- Lead, Halogen, and Antimony Free/RoHS Compliant (Note 1)
- "Green" Devices (Note 2)

#### **Mechanical Data**

- Case: DFN3020B-8 .
- Terminals: Pre-Plated NiPdAu leadframe
- Nominal package height: 0.8mm
- UL Flammability Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Solderable per MIL-STD-202, Method 208
- Weight: 0.013 grams (approximate)

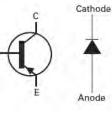
## Applications

- DC DC Converters
- Charging circuits
- Mobile phones
- Motor control

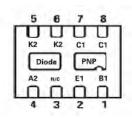
DFN3020B-8



Top View



Device symbol



**Pin Configuration** 

#### **Ordering Information**

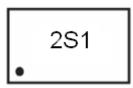
Product	Status	Package	Marking	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXTPS718MCTA	Active	DFN3020B-8	2S1	7	8	3000

Notes:

1. No purposefully added lead. Halogen and Antimony Free.

2. Diodes Inc's "Green" Policy can be found on our website https://www.diodes.com

## **Marking Information**



2S1 = Product type Marking Code Dot Denotes Pin 1



#### **Maximum Ratings, Transistor**

Parameter	Symbol	Limit	Unit
Collector-Base Voltage	V <sub>CBO</sub>	-25	V
Collector-Emitter Voltage	V <sub>CEO</sub>	-20	V
Emitter-Base Voltage	V <sub>EBO</sub>	-7.5	V
Peak Pulse Current	ICM	-6	А
Continuous Collector Current (Note a and f)	Ic	-3.5	A
Base Current	IB	1	A

### **Thermal Characteristics, Transistor**

Characteristic	Symbol	Value	Unit
Power Dissipation at $T_A = 25^{\circ}C$ (Notes a and f) Linear Derating Factor	PD	1.5 12	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes b and f) Linear Derating Factor	PD	2.45 19.6	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes c and f) Linear Derating Factor	P <sub>D</sub>	1 8	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes d and f) Linear Derating Factor	PD	1.13 9	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes d and g) Linear Derating Factor	P <sub>D</sub>	1.7 13.6	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes e and g) Linear Derating Factor	PD	3 24	W mW/°C
Junction to Ambient (Notes a and f)	$R_{ ext{ heta}JA}$	83	°C/W
Junction to Ambient (Notes b and f)	R <sub>0</sub> JA	51	°C/W
Junction to Ambient (Notes c and f)	R <sub>0JA</sub>	125	°C/W
Junction to Ambient (Notes d and f)	R <sub>0JA</sub>	111	°C/W
Junction to Ambient (Notes d and g)	R <sub>0JA</sub>	73.5	°C/W
Junction to Ambient (Notes e and g)	R <sub>0JA</sub>	41.7	°C/W
Junction Temperature	TJ	150	°C
Storage Temperature Range	T <sub>STG</sub>	-55 to +150	°C

a. For a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

b. Measured at t <5 secs for a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device. c. For a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with minimal lead connections only.

d. For a dual device surface mounted on 10 sq cm single sided 1 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The

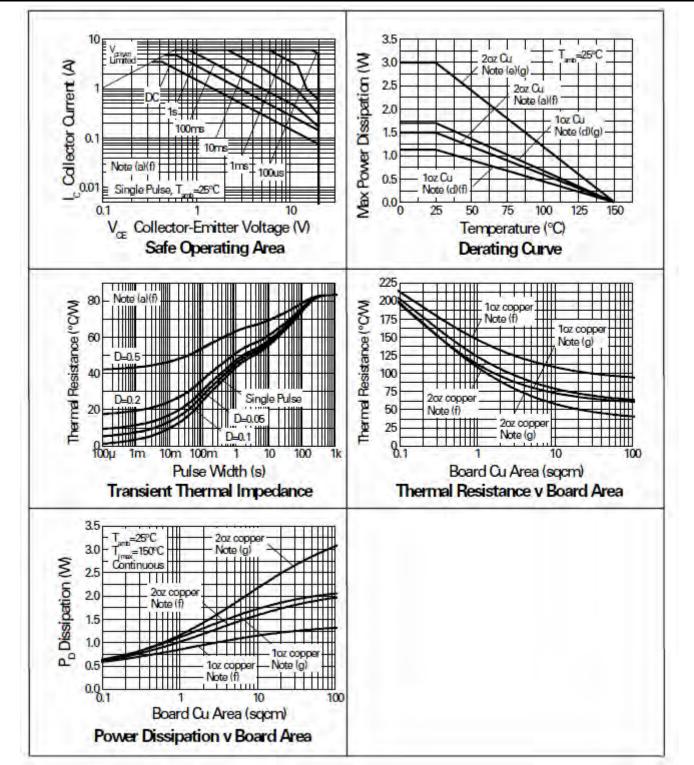
copper area is split down the centre line into two separate areas with one half connected to each half of the dual device. e. For a dual device surface mounted on 85 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device

f. For a dual device with one active die.

Notes:

g. For dual device with 2 active die running at equal power.





# Thermal Characteristics and Derating information, Transistor



#### Maximum Ratings, Schottky Diode

Parameter	Symbol	Limit	Unit
Continuous Reverse Voltage	V <sub>R</sub>	40	V
Forward Voltage @ I <sub>F</sub> = 1000mA (typ)	VF	425	mV
Forward Current	lF	1850	mA
Average Peak Forward Current D=50%	I <sub>FAV</sub>	3	А
Non Repetitive Forward Current t≤ 100µs	1=	12	А
t≤ 10ms	IFSM	7	A

## **Thermal Characteristics, Schottky Diode**

Characteristic	Symbol	Value	Unit
Power Dissipation at $T_A = 25^{\circ}C$ (Notes a and f) Linear Derating Factor	PD	1.2 12	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes b and f) Linear Derating Factor	PD	2 20	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes c and f) Linear Derating Factor	PD	0.8 8	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes d and f) Linear Derating Factor	PD	0.9 9	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes d and g) Linear Derating Factor	PD	136 13.6	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes e and g) Linear Derating Factor	PD	2.4 24	W mW/°C
Junction to Ambient (Notes a and f)	R <sub>θJA</sub>	83	°C/W
Junction to Ambient (Notes b and f)	R <sub>0JA</sub>	51	°C/W
Junction to Ambient (Notes c and f)	R <sub>θJA</sub>	125	°C/W
Junction to Ambient (Notes d and f)	R <sub>0JA</sub>	111	°C/W
Junction to Ambient (Notes d and g)	R <sub>θJA</sub>	73.5	°C/W
Junction to Ambient (Notes e and g)	R <sub>θJA</sub>	41.7	°C/W
Junction Temperature	TJ	125	°C
Storage Temperature Range	T <sub>STG</sub>	-55 to +150	С°

a. For a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper Notes:

area is split down the centre line into two separate areas with one half connected to each half of the dual device. b. Measured at t <5 secs for a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads

attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device. c. For a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with minimal lead connections only.

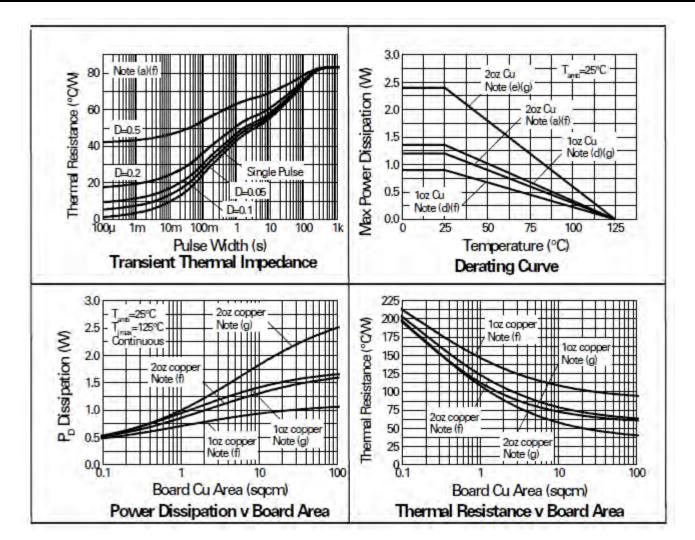
d. For a dual device surface mounted on 10 sq cm single sided 1 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

e. For a dual device surface mounted on 85 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

f. For a dual device with one active die.

g. For dual device with 2 active die running at equal power.





# Thermal Characteristics and Derating information, Schottky Diode



### Electrical Characteristics, Transistor @T<sub>A</sub> = 25°C unless otherwise specified

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
Collector-Base Breakdown Voltage	V <sub>(BR)CBO</sub>	-25	-35	-	V	$I_{\rm C} = -100 \mu {\rm A}$
Collector-Emitter Breakdown Voltage (Note 3)	V <sub>(BR)CEO</sub>	-20	-25	-	V	$I_{\rm C} = -10 {\rm mA}$
Emitter-Base Breakdown Voltage	V <sub>(BR)EBO</sub>	-7.5	-8.5	-	V	I <sub>E</sub> = -100μA
Collector Cutoff Current	I <sub>CBO</sub>	-	-	-25	nA	$V_{CB} = -20V$
Emitter Cutoff Current	I <sub>EBO</sub>	-	-	-25	. nA	V <sub>EB</sub> = -6V
Collector Emitter Cutoff Current	I <sub>CES</sub>	-	-	-25	nA	V <sub>CES</sub> = -16V
Static Forward Current Transfer Ratio (Note 3)	h <sub>FE</sub>	300 300 150 15	475 450 230 30	- - -	-	$\begin{split} I_{C} &= -10 \text{mA}, \ V_{CE} &= -2 \text{V} \\ I_{C} &= -100 \text{mA}, \ V_{CE} &= -2 \text{V} \\ I_{C} &= -2 \text{A}, \ V_{CE} &= -2 \text{V} \\ I_{C} &= -6 \text{A}, \ V_{CE} &= -2 \text{V} \end{split}$
Collector-Emitter Saturation Voltage (Note 3)	V <sub>CE(sat)</sub>		-19 -170 -190 -240 -225	-30 -220 -250 -350 -300	mV	$ \begin{array}{l} I_{C}=-0.1A, \ I_{B}=-10 \text{mA} \\ I_{C}=-1A, \ I_{B}=-20 \text{mA} \\ I_{C}=-1.5A, \ I_{B}=-50 \text{mA} \\ I_{C}=-2.5A, \ I_{B}=-150 \text{mA} \\ I_{C}=-3.5A, \ I_{B}=-350 \text{mA} \end{array} $
Base-Emitter Turn-On Voltage (Note 3)	V <sub>BE(on)</sub>	-	-0.87	-0.95	V	I <sub>C</sub> = -3.5A, V <sub>CE</sub> = -2V
Base-Emitter Saturation Voltage (Note 3)	V <sub>BE(sat)</sub>	-	-1.10	-1.075	V	I <sub>C</sub> = -3.5A, I <sub>B</sub> = -350mA
Output Capacitance	C <sub>obo</sub>	-	21	30	pF	V <sub>CB</sub> = -10V. f = 1MHz
Transition Frequency	f <sub>T</sub>	150	180	-	MHz	$V_{CE} = -10V, I_C = -50mA, f = 100MHz$
Turn-on Time	t <sub>on</sub>	-	40	-	ns	$V_{CC} = -10V, I_{C} = -1A$
Turn-off Time	t <sub>off</sub>	-	670	-	ns	$I_{B1} = I_{B2} = -50 \text{mA}$

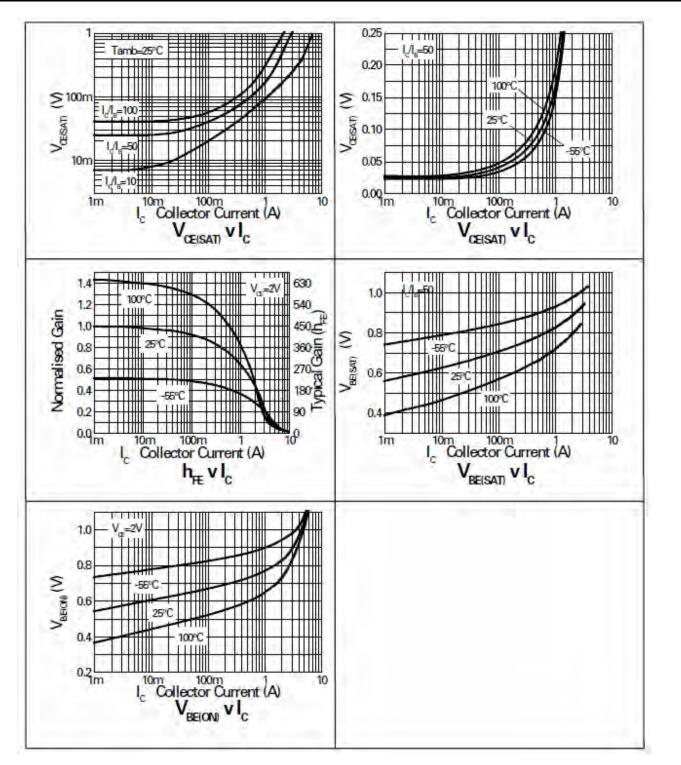
# Electrical Characteristics, Schottky Diode @T<sub>A</sub> = 25°C unless otherwise specified

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
Reverse Breakdown Voltage	V <sub>(BR)R</sub>	40	60	-	V	I <sub>R</sub> = -300μA
Forward Voltage (Note 3)	VF		240 265 305 355 390 425 495 420	270 290 340 400 450 500 600	mV	$I_{F} = 50mA \\ I_{F} = 100mA \\ I_{F} = 250mA \\ I_{F} = 500mA \\ I_{F} = 750mA \\ I_{F} = 1000mA \\ I_{F} = 1500mA \\ I_{F} = 1000mA, T_{A} = 100^{\circ}C$
Reverse Current	I <sub>R</sub>	-	50	100	μA	$V_R = 30V$
Diode Capacitance	CD	-	25	-	pF	$V_{R} = 25V, f = 1MHz$
Reverse Recovery Time	t <sub>rr</sub>	-	12	-	ns	switched from I <sub>F</sub> = 500mA to I <sub>R</sub> = 500mA Measured at I <sub>R</sub> = 50mA

Notes: 3. Measured under pulsed conditions.

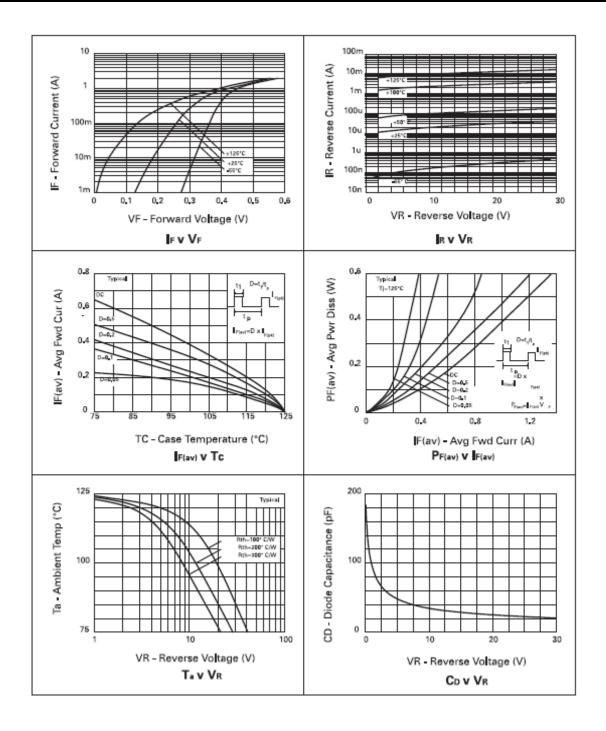


# **Typical Characteristics, Transistor**



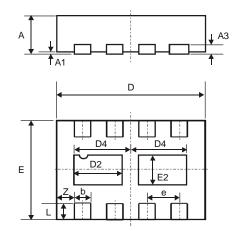


# Typical Characteristics, Schottky Diode



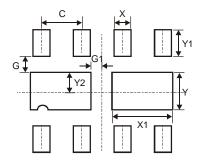


# **Package Outline Dimensions**



	DFN3020B-8					
Dim	Min	Max	Тур			
Α	0.77	0.83	0.80			
A1	0	0.05	0.02			
A3	-	-	0.15			
b	0.25	0.35	0.30			
D	2.95	3.075	3.00			
D2	0.82	1.02	0.92			
D4	1.01	1.21	1.11			
е	-	-	0.65			
Е	1.95	2.075	2.00			
E2	0.43	0.63	0.53			
L	0.25	0.35	0.30			
Ζ	-	-	0.375			
All I	All Dimensions in mm					

# Suggested Pad Layout



Dimensions	Value (in mm)			
C	0.650			
G	0.285			
G1	0.090			
Х	0.400			
X1	1.120			
Ý	0.730			
Y1	0.500			
Y2	0.365			



#### IMPORTANT NOTICE

DIODES INCORPORATED MAKES NO WARRANTY OF ANY KIND, EXPRESS OR IMPLIED, WITH REGARDS TO THIS DOCUMENT, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION).

Diodes Incorporated and its subsidiaries reserve the right to make modifications, enhancements, improvements, corrections or other changes without further notice to this document and any product described herein. Diodes Incorporated does not assume any liability arising out of the application or use of this document or any product described herein; neither does Diodes Incorporated convey any license under its patent or trademark rights, nor the rights of others. Any Customer or user of this document or products described herein in such applications shall assume all risks of such use and will agree to hold Diodes Incorporated and all the companies whose products are represented on Diodes Incorporated website, harmless against all damages.

Diodes Incorporated does not warrant or accept any liability whatsoever in respect of any products purchased through unauthorized sales channel. Should Customers purchase or use Diodes Incorporated products for any unintended or unauthorized application, Customers shall indemnify and hold Diodes Incorporated and its representatives harmless against all claims, damages, expenses, and attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized application.

Products described herein may be covered by one or more United States, international or foreign patents pending. Product names and markings noted herein may also be covered by one or more United States, international or foreign trademarks.

#### LIFE SUPPORT

Diodes Incorporated products are specifically not authorized for use as critical components in life support devices or systems without the express written approval of the Chief Executive Officer of Diodes Incorporated. As used herein:

- A. Life support devices or systems are devices or systems which:
  - 1. are intended to implant into the body, or
  - 2. support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in significant injury to the user.
- B. A critical component is any component in a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or to affect its safety or effectiveness.

Customers represent that they have all necessary expertise in the safety and regulatory ramifications of their life support devices or systems, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of Diodes Incorporated products in such safety-critical, life support devices or systems, notwithstanding any devicesor systems-related information or support that may be provided by Diodes Incorporated. Further, Customers must fully indemnify Diodes Incorporated and its representatives against any damages arising out of the use of Diodes Incorporated products in such safety-critical, life support devices or systems.

Copyright © 2009, Diodes Incorporated

www.diodes.com